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# **2022 IEEE International Electron Devices Meeting**

December 3rd - 7th, 2022

### **Focused Call for Papers**

IEDM is pleased to announce increased technical focus in the area of:

## Reliability of Systems & Devices (RSD)

### **Topics**

Papers are solicited in the following themes of interest:

- Reliability of FEOL/MEOL/BEOL, latch-up, and ESD;
- Design for reliability and variability-aware design,
- Robustness and security of electronic circuits and systems.
- Reliability of devices and systems for memory, biomedical, automotive and aerospace
- Reliable systems with unreliable devices
- Reliability of cryogenic devices for future quantum computing applications
- Noise characterization

New or trending areas include:

- Degradation mechanisms of emerging memories
- Reliability of devices, circuits and systems for more-than-Moore such as bio and DNA
- Reliability of automotive and aerospace devices circuits and systems

### **Paper Submission**

Submission deadline: July 14th Single submission of final, four-page paper